

Supporting information

The solvent engineering by ACN for the growth of high quality

CsPbBr₃ single crystals

Kunpeng Mou^a, Xiaoxi Feng^b, Fangxiong Tang^b, Wenzhen Wang^c, Xudong Tang^{b,d},
Yongning Liu^a, Benlan Zeng^a, Sirui Bao^b, Minghao Cui^{b,d}, Jianing Hu^a, Huaxing Gou^a,
Yan Zhu^{a,*}, Jinkun Liu^a, Run Xu^{b,d,*}

^a Faculty of Materials Science and Technology, Kunming University of Science and Technology, Kunming 650093, China

^b School of Materials Science and Engineering, Shanghai University, Shanghai 200444, China

^c Shanghai Technical Institute of Electronics & Information, 3098 Wahong Road, Shanghai 201411, China

^d Zhejiang Institute of Advanced Materials, Shanghai University, 1588 Huaxiang Street, Jiashan 314113, Zhejiang, China.

* Corresponding author:

Yan Zhu (zhuyan@kust.edu.cn); Run Xu (runxu@staff.shu.edu.cn)



Fig.S1 Schematic diagram of the solution-growth process of CsPbBr₃ single crystal with ACN addition (molar ratios in the figure are indicated).

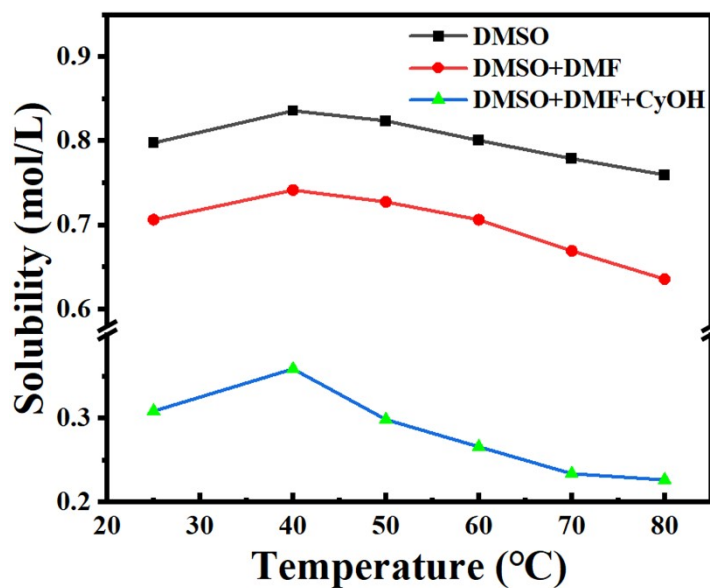


Fig. S2 Solubility curves of CsPbBr₃ in DMSO, DMSO/DMF, and DMSO/DMF/CyOH.

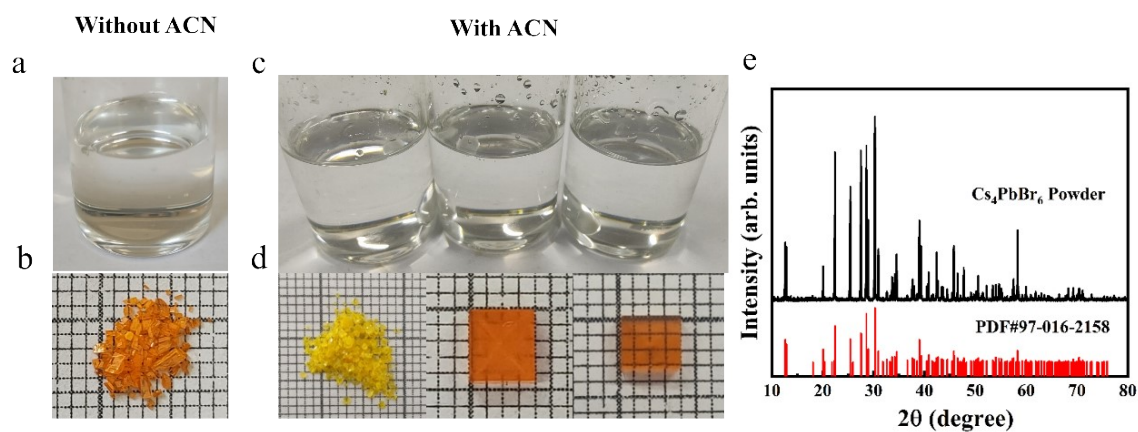


Fig. S3 (a) Precursor solution prepared using DMSO as the solvent. (b) Crystals grown from the solution in Fig. S2a. (c) Precursor solutions prepared using DMSO, a volume ratio of 4:1 of DMSO to DMF, and a volume ratio of 3:1 of DMSO to DMF as solvents. (d) Crystals have grown after adding ACN to each system in Fig. S2c. (e) Powder XRD characterization of the yellow-green crystals obtained using DMSO as the solvent and adding ACN as shown in Fig. S2d.

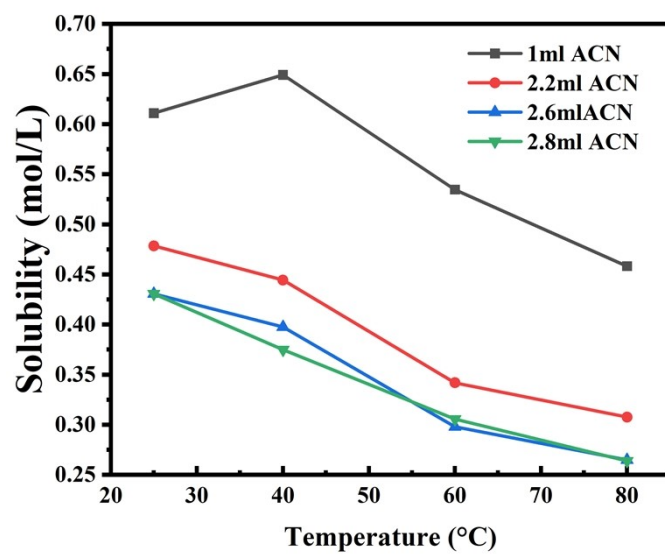


Fig. S4 The solubility curves of CsPbBr₃ under different ACN addition amounts.

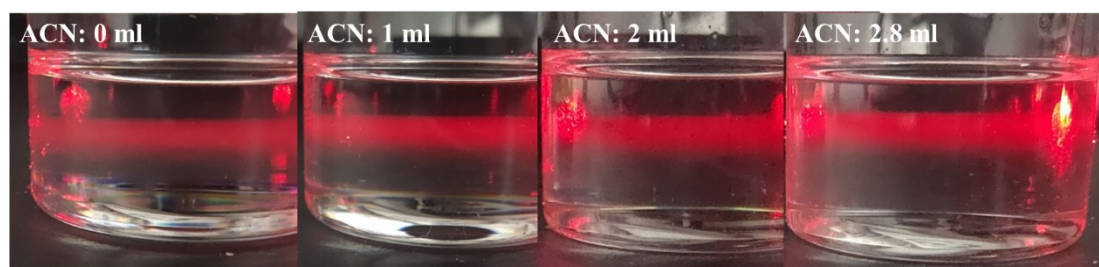


Fig. S5 Tyndall effect, in precursor solutions of the same concentration but with various amounts of ACN, respectively.

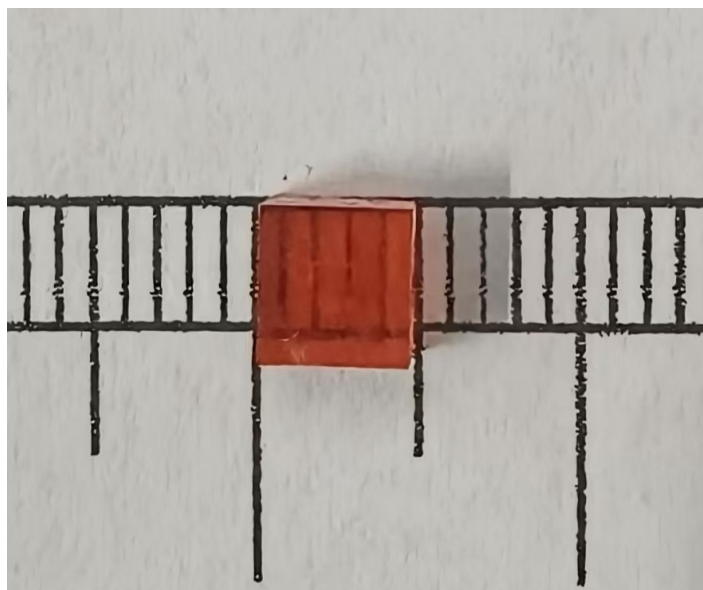


Fig. S6 Photograph of CsPbBr₃ crystals growing in the DMSO/DMF/CyOH solvent.

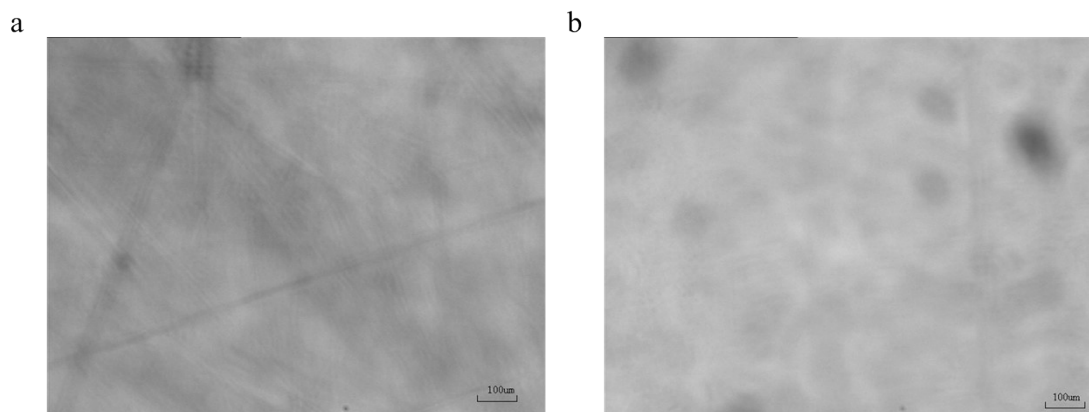


Fig. S7 (a) Infrared transmission images of CsPbBr₃ single crystal after polishing and (b) the same crystal after 8 months under a controlled environment (humidity < 40%).

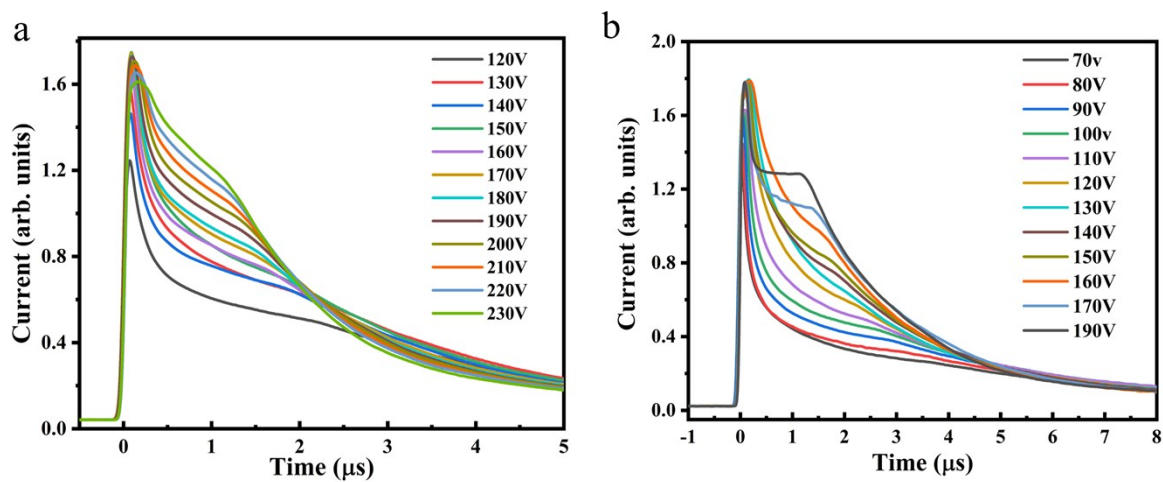


Fig. S8 (a) Electron and (b) Hole ToF spectra under different biases.

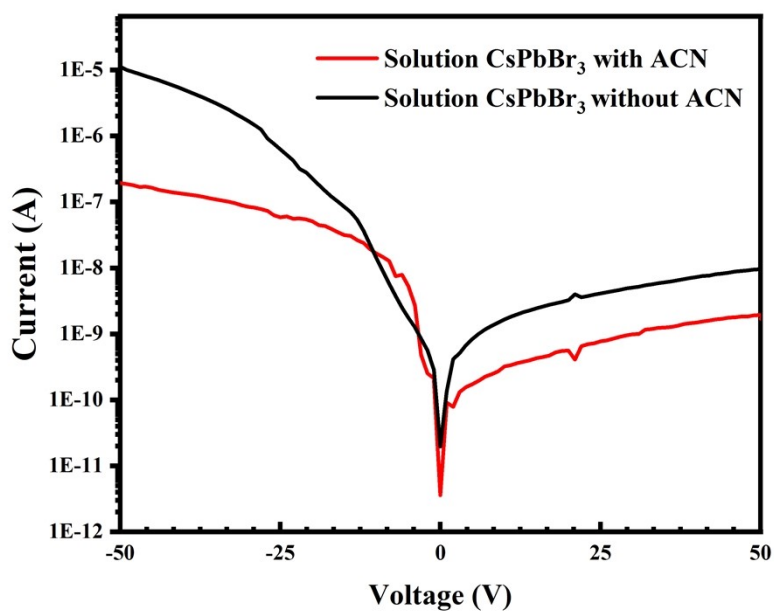


Fig. S9 The dark current of CsPbBr₃ crystals grown with and without ACN.

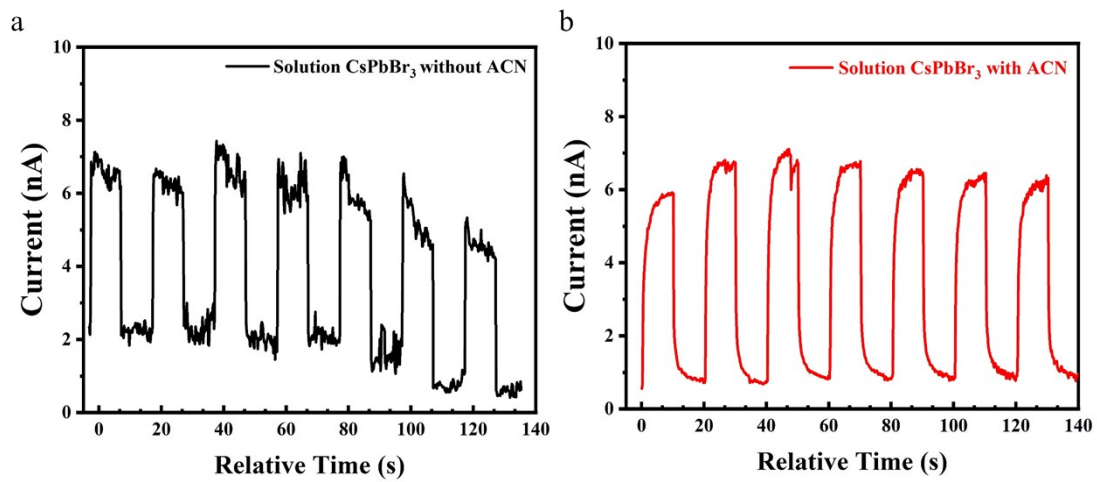


Fig. S10 X-ray response at a bias voltage of 5 V and an incident dose rate of $1.6 \mu\text{Gy}^{-1}\cdot\text{s}^{-1}$.

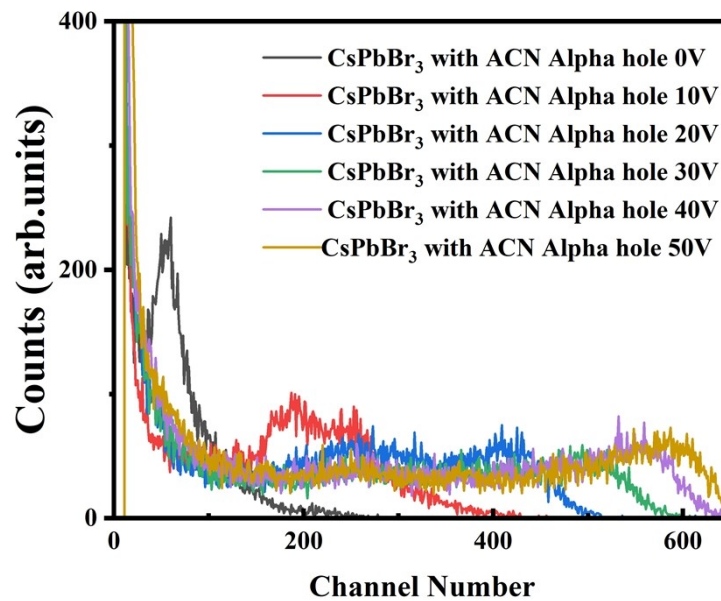


Fig. S11 Alpha-particle energy spectra irradiated by ^{241}Am under different biases.

Table S1 Summary of the growth of CsPbBr₃ single crystals.

Researcher	Solvent	Additives	Growth method	Growth temperature (°C)	XRC (°)	τ or $\mu\tau$ (ns or cm ² /V)	Transmittance (%)
Sujith <i>et al.</i> [26]	DMSO	none	LTC ^a	27-30	none	none	none
Gao <i>et al.</i> [27]	DMSO	none	ITC ^b	110	none	$\tau_2=17.03$	none
Chen <i>et al.</i> [28]	DMSO	none	ITC ^b	140	0.043	none	none
Feng <i>et al.</i> [19]	DMSO	Choline Bromide	ITC ^b	80-85	none	$\mu\tau_c=1.80 \times 10^{-3}$	none
Pan <i>et al.</i> [29]	DMSO	TMAB	ITC ^b	60-85	none	$\tau_{ave}=88$	none
Dirin <i>et al.</i> [23]	DMSO/DMF/ CyOH	none	ITC ^b	90-110	none	$\mu\tau=2 \times 10^{-4}$	none
Zhang <i>et al.</i> [24]	DMSO/DMF/ CyOH	none	ITC ^b	49.5	none	$\tau_1 = 2.9;$ $\tau_2 = 25.1$	74%
Cheng <i>et al.</i> [25]	DMSO/DMF/ CyOH	none	ITC ^b	50-90	none	none	none
Wang <i>et al.</i> [30]	DMSO/DMF/ CyOH	none	ITC ^b	40-80	none	$\mu\tau=2.8 \times 10^{-4}$	none
Cheng <i>et al.</i> [31]	DMSO/DMF/ CyOH	Choline Bromide	ITC ^b	below 85	0.082	$\tau_1=0.70$ $\tau_2=6.51$	none
Xue <i>et al.</i> [32]	DMSO	Bromoacetic acid	ITC ^b	105	0.07	$\tau=80$	none

a LTC: Low-temperature crystallization; b ITC: Inverse temperature crystallization

References

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